

<b>Notice of References Cited</b>	Application/Control No. 10/508,945	Applicant(s)/Patent Under Reexamination SUDA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,224,686	05-2001	Aoki et al.	148/230
	B	US-			
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	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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